



## Product/Process Change Notice - PCN 22\_0092 Rev. -

Analog Devices, Inc. One Analog Way, Wilmington, MA 01887

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

**PCN Title:** LTC2949 Die Revision Change

**Publication Date:** 04-May-2022

**Effectivity Date:** 06-Aug-2022 *(the earliest date that a customer could expect to receive changed material)*

### Revision Description:

Initial Release

### Description Of Change:

1. Performed a layout correction at a PMOS-transistor-type that had created a yield loss at Under-Voltage-Lockout-Blocks in former production runs.
2. Increased the internal trim-range at the VREF-block
3. Centered the internal trim-ranges at the internal oscillators
4. Improved the layout of certain resistive voltage dividers to improve matching of these structures

### Reason For Change:

1. The layout change is to minimize performance variations and to ensure stable yield in production.
2. To adapt better to usual parameter variations to ensure stable and robust production yield.
3. To ensure stable and robust production yield
4. To ensure stable and robust production yield

### Impact of the change (positive or negative) on fit, form, function & reliability:

There is no change in form, fit, function, quality or reliability of these products.

### Product Identification *(this section will describe how to identify the changed material)*

The parts that will be assembled with new die will be identified by Date Code.

### Summary of Supporting Information:

Qualification will be performed per AEC-Q100, Stress Test Qualification for Integrated Circuits. See attached Qualification Results.

### Comments

The die change was qualified by performing characterization over the full operating junction temperature range and through rigorous engineering evaluation. In addition, the product successfully completed ESD and Latch Up. stress testing.

### Supporting Documents

**Attachment 1: Type:** Qualification Results Summary

ADI\_PCN\_22\_0092\_Rev\_-\_LTC2949 PCN Summary Report.pdf

**Attachment 2: Type:** Delta Qualification Matrix

ADI\_PCN\_22\_0092\_Rev\_-\_LTC2949 PCN\_22\_0092 PCN-Delta-Qualification-Matrix-ZVEI-5\_0\_9.xlsm

**For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.**

Americas:

Europe:

Japan:

Rest of Asia:



**Appendix A - Affected ADI Models**

**Added Parts On This Revision - Product Family / Model Number (6)**

LTC2949 / LTC2949HLXE#30XPBF	LTC2949 / LTC2949HLXE#30YPBF	LTC2949 / LTC2949HLXE#3ZZPBF	LTC2949 / LTC2949HLXE#3ZZTRPBF	LTC2949 / LTC2949LXE#3ZZPBF
LTC2949 / LTC2949LXE#3ZZTRPBF				

**Appendix B - Revision History**

<b>Rev</b>	<b>Publish Date</b>	<b>Effectivity Date</b>	<b>Rev Description</b>
Rev. -	04-May-2022	06-Aug-2022	Initial Release

Analog Devices, Inc.

DocId:8873 Parent DocId:None Layout Rev:8